

FDP5800

N-Channel Logic Level PowerTrench $^{\circledR}$ MOSFET 60V,80A, 6m Ω

Features

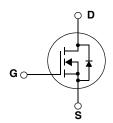
- $R_{DS(on)}$ = 4.6m Ω (Typ.), V_{GS} = 10V, I_D = 80A
- High performance trench technology for extermly low Rdson
- · Low gate Charge
- · High power and current handing capability
- RoHs Compliant



Applications

- · Motor/ Body Load Control
- Power Train Management
- · Injection Systems
- DC-AC Converters and UPS





MOSFET Maximum Ratings T_C = 25°C unless otherwise noted*

Symbol		Parameter	Ratings	Units
V_{DSS}	Drain-Source Voltage		60	V
V_{GSS}	Gate-Source Voltage		±20	V
		-Continuous (T _C = 25°C)	80	Α
I _D	Drain Current	-Continuous (T _C = 100°C)	80*	Α
		-Continuous (T _A = 25°C)	14	Α
I _{DM}	Drain Current	- Pulsed	320	Α
E _{AS}	Single Pulsed Avalanch	ne Energy (Note 1)	652	mJ
В	Power Dissipation	(T _C = 25°C)	242	W
P_{D}		- Derate above 25°C	1.61	W/°C
T _J , T _{STG}	Operating and Storage	Temperature Range	-55 to +175	°C

^{*}Drain current limited by package

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance , Junction to Case	0.62	°C/W
$R_{\theta JA}$	Thermal Resistance , Junction to Ambient, 1in ² copper pad area	43	°C/W
$R_{\theta JA}$	Thermal Resistance , Junction to Ambient	62.5	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDP5800	FDP5800	TO220			50

Electrical Characteristics T_C= 25°C unless otherwise noted

Symbol	Parameter	Conditions	Min	Тур	Max	Units
Off Charac	teristics					
B _{VDSS}	Drain-Source Breakdown Voltage	$I_D = 250 \mu A$, $V_{GS} = 0V$, $T_J = 25^{\circ}C$	60			V
1	Zero Gate Voltage Drain Current	V _{DS} = 48V			1	μΑ
DSS	Zero Gate Voltage Drain Current	$V_{GS} = 0V$ $T_J = 150^{\circ}C$			500	μΑ
I _{GSS}	Gate-Body Leakage Current, Forward	$V_{GS} = \pm 20V$, $V_{DS} = 0V$			±100	nA

On Characteristics

V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	1.0		2.5	V
		$V_{GS} = 10V$, $I_{D} = 80A$		4.6	6.0	$m\Omega$
		V _{GS} =4.5V , I _D = 80A		5.9	7.2	mΩ
R _{DS(on)}	Static Drain-Source On Resistance	V _{GS} = 5V , I _D = 80A		5.6	7.0	mΩ
		V _{GS} =10V, I _D = 80A T _J = 175°C		10.4	12.6	mΩ

Dynamic Characteristics

C _{iss}	Input Capacitance	\/ 45\/\/ 0	n /	 6890	9160	pF
C _{oss}	Output Capacitance	$V_{DS} = 15V, V_{GS} = 0$ f = 1MHz	IV .	 750	1000	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1101112		 295	445	pF
R_G	Gate Resistance	V _{GS} = 0.5V, f = 1M	Hz	 1.2		Ω
$Q_{g(TOT)}$	Total Gate Charge at 10V	V _{GS} = 0V to 10V		 112	145	nC
$Q_{g(TH)}$	Total Gate Charge at 5V	V _{GS} = 0V to 5V	1,,	 58		nC
$Q_{g(TH)}$	Threshold Gate Charge	V _{GS} = 0V to 1V	$V_{DS} = 30V$ $I_{D} = 80A$	 7.0		nC
Q_{gs}	Gate to Source Gate Charge		$I_D = 80A$ $I_a = 1mA$	 23		nC
Q _{gs2}	Gate Charge Threshold to Plateau		.g	 13		nC
Q_{gd}	Gate to Drain "Miller" Charge			 18		nC

Switching Characteristics ($V_{GS} = 10V$)

t_{ON}	Turn-On Time			37	85	ns
t _{d(on)}	Turn-On Delay Time			18	46	ns
t _r	Turn-On Rise Time	V_{DD} = 30V, I_{D} = 80A V_{GS} = 10V, R_{GEN} = 1.5 Ω	-	19	47	ns
t _{d(off)}	Turn-Off Delay Time	V _{GS} = 10V, R _{GEN} = 1.512		55	120	ns
t _f	Turn-Off Fall Time			9	28	ns
t _{OFF}	Turn-Off Time			64	138	ns

Drain-Source Diode Characteristics

V	Drain-Source Diode Forward Voltage	V _{GS} = 0V, I _{SD} = 80A	 	1.25	V
V_{SD}	Diam-Source Diode 1 ofward voltage	$V_{GS} = 0V, I_{SD} = 40A$	 -	1.0	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0V, I _{SD} = 60A	 58		ns
Q _{rr}	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s$	 106		nC

Notes: 1: L = 1mH, I_{AS} = 36A, V_{DD} = 54V, V_{GS} = 10V, R_{G} = 25 Ω , Starting T_{J} = 25 $^{\circ}$ C

Typical Performance Characteristics

Figure 1. On-Region Characteristics

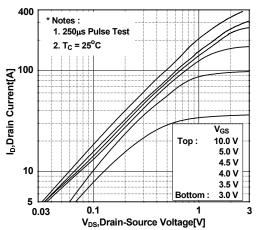


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

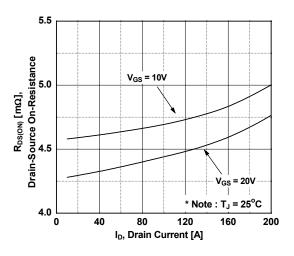


Figure 5. Capacitance Characteristics

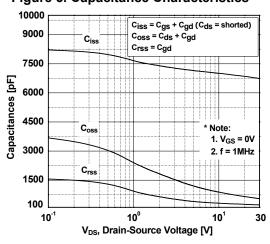


Figure 2. Transfer Characteristics

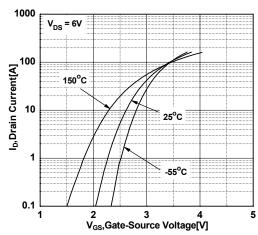


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

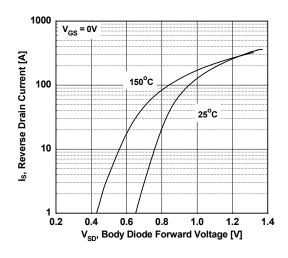
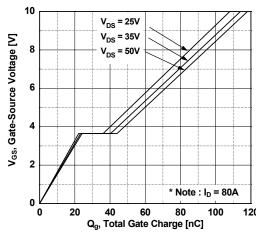


Figure 6. Gate Charge Characteristics



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Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

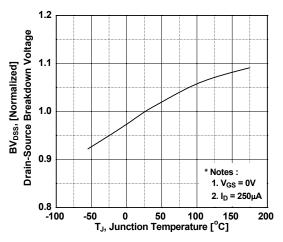


Figure 9. Maximum Safe Operating Area

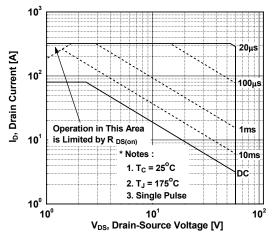


Figure 8. On-Resistance Variation vs. Temperature

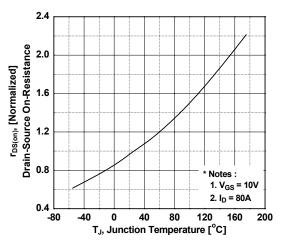


Figure 10. Maximum Drain Current vs. Case Temperature

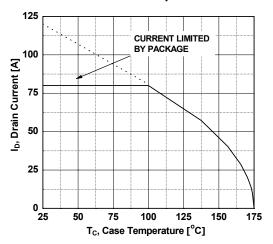
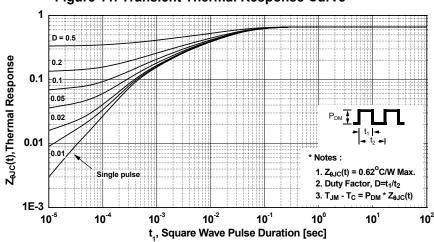
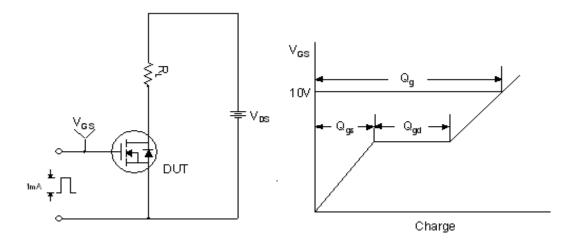


Figure 11. Transient Thermal Response Curve

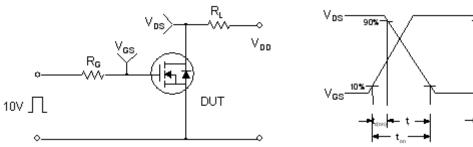


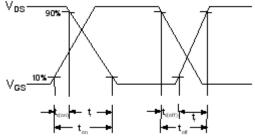
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Gate Charge Test Circuit & Waveform

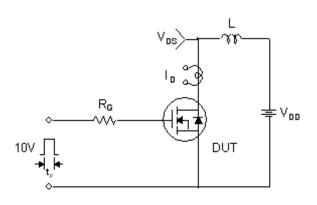


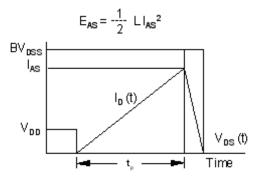
Resistive Switching Test Circuit & Waveforms



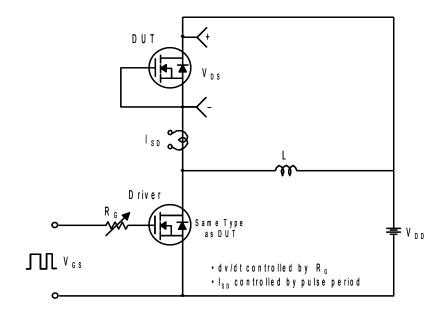


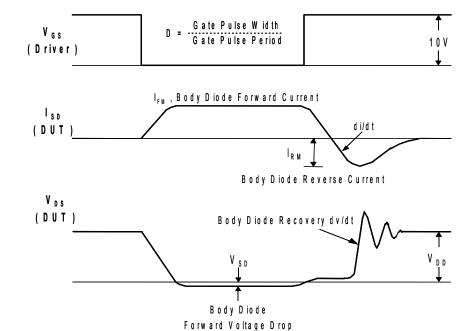
Unclamped Inductive Switching Test Circuit & Waveforms





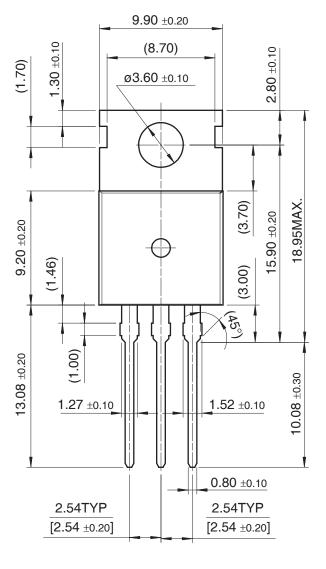
Peak Diode Recovery dv/dt Test Circuit & Waveforms

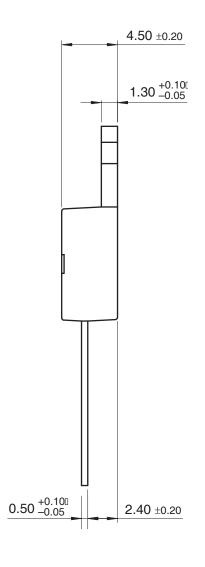




Mechanical Dimensions

TO-220







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